

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/694,737	TSAI, ROGER YEN-LUEN	
Examiner			Jaime Cardenas-Navia	Art Unit 3624	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0133444 A1	09-2002	Sankaran et al.	705/36
*	B	US-2002/0161674 A1	10-2002	Scheer, Robert H.	705/28
*	C	US-2003/0088449 A1	05-2003	Menninger, Anthony Frank	705/8
*	D	US-2004/0254825 A1	12-2004	Hsu et al.	705/008
*	E	US-2005/0060164 A1	03-2005	ELI BERL ILLION, BRIAN	705/001
*	F	US-2005/0075920 A1	04-2005	Li et al.	705/010
*	G	US-2006/0246436 A1	11-2006	Ohno et al.	435/006
*	H	US-7,236,940 B2	06-2007	Chappel, Oscar A.	705/10
*	I	US-2007/0192160 A1	08-2007	Nephew et al.	705/010
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.